## Search Notes



Application/Control No.

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Reexamination

Applicant(s)/Patent Under

Examiner

Kim, John

**Art Unit** 

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## **SEARCHED**

Class	Subclass	Date	Examiner
210	198.2, 263, 283, 287, 289, 290, 291, 435, 446, 456, 483, 484, 488, 489, 490, 491, 502.1, 503, 505	6/15/06	JK
422	58, 59, 60, 69, 70, 101, 102, 104	6/15/06	JK
530	412, 413, 416, 417	6/15/06	JK
502	401, 405	6/15/06	JK
436	177, 178, 527	6/1/065	JK
Updated Search Above		12/13/06	JK
Updated Search Above		4/24/07	JK
Updated Search Above		11/11/07	JK

## **SEARCH NOTES**

Search Notes	Date	Examiner
JK	6/15/06	JK
EAST Search Note	6/15/06	JK
EAST Search Note	11/11/07	JK

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